

<b>Search Notes</b> 	<b>Application/Control No.</b> 09/619,917	<b>Applicant(s)/Patent under Reexamination</b> NOMURA ET AL.
	<b>Examiner</b> Nhan T. Tran	<b>Art Unit</b> 2622

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner